PROCEEDINGS OF SPIE

Photonic Instrumentation Engineering X

Lynda E. Busse Yakov Soskind Editors

30 January – 1 February 2023 San Francisco, California, United States

Sponsored and Published by SPIE

Volume 12428

Proceedings of SPIE 0277-786X, V. 12428

SPIE is an international society advancing an interdisciplinary approach to the science and application of light.

Photonic Instrumentation Engineering X, edited by Lynda E. Busse, Yakov Soskind, Proc. of SPIE Vol. 12428, 1242801 · © 2023 SPIE · 0277-786X · doi: 10.1117/12.2677015

Proc. of SPIE Vol. 12428 1242801-1

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ISSN: 0277-786X ISSN: 1996-756X (electronic)

ISBN: 9781510659612 ISBN: 9781510659629 (electronic)

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